

*PATENT*

**IN THE UNITED STATES PATENT AND  
TRADEMARK OFFICE**

Inventor:	Buxton, et al.	Docket No.:	TAI.0800
Serial No.:	10/730,388	Examiner:	Khuu, Cindy D.
Filing Date:	December 07, 2003	Art Unit:	2863
Title:	Methods and Apparatus for Data Analysis		

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner of Patents  
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Alexandria, Virginia 22313-1450

Commissioner:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §§1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner.

The applicant further provides the following information for which no written references are possessed:

- The article: Variance Reduction Using Wafer Patterns, Daasch, McNames, Bockelman, Cota (2003);
- The company LSI may have a commercial SPP solution using Nearest-Neighbor Residual (NNR) technology that may be relevant; and
- Mr. Charles Meyerson of Medtronic may have information about LSI's NNR/SPP techniques that may be relevant.

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Serial No.: 10/730,388  
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The preceding information and the attached references are cited only in the interest of candor and without any admission that they constitute statutory prior art or contain matter which anticipates the invention or which would render the same obvious, either singly or in combination, to a person of ordinary skill in the art.

This Information Disclosure Statement (IDS) is being filed under 37 C.F.R. §1.97(c) before the mailing date of any final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311, or an action that otherwise closes prosecution of the application. The IDS is accompanied by the fee set forth in 37 C.F.R. §1.17(p). If there are any questions concerning this IDS, the Examiner is requested to contact the undersigned.

Respectfully submitted,

Date: 22 DEC 06

By:   
Daniel J. Noblitt  
Reg. No. 35,969

**NOBLITT & GILMORE, LLC**  
4800 North Scottsdale Road  
Suite 6000  
Scottsdale, Arizona 85251  
Telephone: 480.994.9859  
Facsimile: 480.994.9025

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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 8

**Complete if Known**

Application Number	10/730,388
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First Named Inventor	Buxton
Art Unit	2863
Examiner Name	KHUU, CINDY
Attorney Docket Number	TAI.0800

**NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		APPLEWHITE. The view from the top. IEEE Spectrum, 41(11 (INT)):18-31, Nov 2004.	
		Canuto, M. Fairhurst and G. Howells, (2001) Improving ARTMap learning through variable vigilance. International Journal of Neural Systems, Vol. 11, No. 6, pp. 509-522.	
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		R. C. Eberhart and J. Kennedy, "A new optimizer using particle swarm theory", in Proc. 6th Intl. Symposium on Micro Machines and Human Science, Nagoya, Japan, IEEE 1995	
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		R.C. Eberhart and Y. Shi, "Comparing inertia weight and constriction factors in particle swarm optimization", in Proc. of the Congress of Evolutionary Computation, 2000	
		F. Chen and S. Liu, "A Neural-Network Approach To Recognize Defect Spatial Pattern in Semiconductor Fabrication", IEEE Transactions on Semiconductor Manufacturing, v.13 2000	

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		T. Fountain, T. Dietterich, and B. Sudyka. Mining IC test data to optimize VLSI testing. the 6th ACM SIGKDD International Conference pages 18-25, 2000	
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		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Test and Test Equipment)	
		K. Kameyama, and Y. Kosugi, "Semiconductor Defect Classification using Hyperellipsoid Clustering Neural Networks and Model Switching", Intl Joint Conf on Neural Networks 1999	

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		T.P. Kamowski, K.W. Tobin, S.S. Gleason, Fred Lakhani, "The Application of Spatial Signature Analysis to Electrical Test Data: Validation Study," SPIE 24th Ann'l Symp Feb1999	
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		R. Mendes, J. Kennedy, and J. Neves. Watch thy neighbor or how the swarm can learn from its environment. IEEE Swarm Intelligence Symposium, pages 88 - 94, April 24-26 2003	
		R. Mendes, J. Kennedy, and J. Neves. The Fully Informed Particle: Simpler, Maybe Better. IEEE Transaction on Evolutionary Computation, 8:204-210, June 2004	

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		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003	
		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004 (PRESENTATION)	
		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004	
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		K. E. Parsopoulos and M. N. Vrahatis. On the Computation of All Global Minimizers through Particle Swarm Optimization. IEEE Transaction on Evolutionary Computation, June 2004	
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		J. Salerno, "Using the particle swarm optimization technique to train a recurrent neural model", IEEE Inter. Conference on Tools with Artificial Intelligence, pp 45-49, 1997	
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		Tseng, L. Y. and Yang, S. B., "Genetic Algorithms for Clustering, Feature Selection and Classification", International Conference on Neural Networks, 9-12 June 1997	

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		Watkins and L. Boggess. A new classifier based on resource limited Artificial Immune Systems. In Congress on Evolutionary Computation CEC'02, vol II, pp 1546-51. IEEE May 2002	
		C. Zhang, H. Shao, and Y. Li, "Particle swarm optimization for evolving artificial neural networks", IEEE Int'l Conf on Systems, Man and Cybernetics vol. 4, 2000	

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		MADGE, ROBERT, et al. Statistical Post-Processing at Wafersort - An Alternative to Burn-in and a Manufacturable Solution to Test Limit Setting for Sub-Micron ..., IEEE 2002	
		MOTOROLA, Process Average Testing (PAT), Statistical Yield Analysis (SYA) and Junction Verification Test (JVT), Aug 03, 98	

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